

TESTING APPARATUS AND METHOD FOR THIN FILM TRANSISTOR DISPLAY ARRAY

ABSTRACT

5 The present invention discloses a testing circuit and method for thin film transistor display array, for testing the yield of thin film transistor array. The testing circuit comprising: An array tester, a test panel (DUT), a sense amplifier array. The sense amplifier is composed by a plurality of trans- impedance amplifier unit and a plurality of parasitic capacitance
10 discharge circuit unit. Every sense amplifier includes: a trans-impedance amplifier, which is implemented by an operational amplifier, two switches and an operation capacitance, the trans-impedance amplifier is used to form an integrated circuit, the output is transmitted to a sampling/hold circuit via a switch; a parasitic capacitance discharge circuit is used to form
15 a discharge rout for the charge of the parasitic capacitance.